



PRODUCT DATA



Micro International, Inc

PART NUMBER

LDT5087 and LDT5087T

Micro-LID PNP Transistor



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**Micro-LID Transistors
LDT5087 and LDT5087T**

Description:

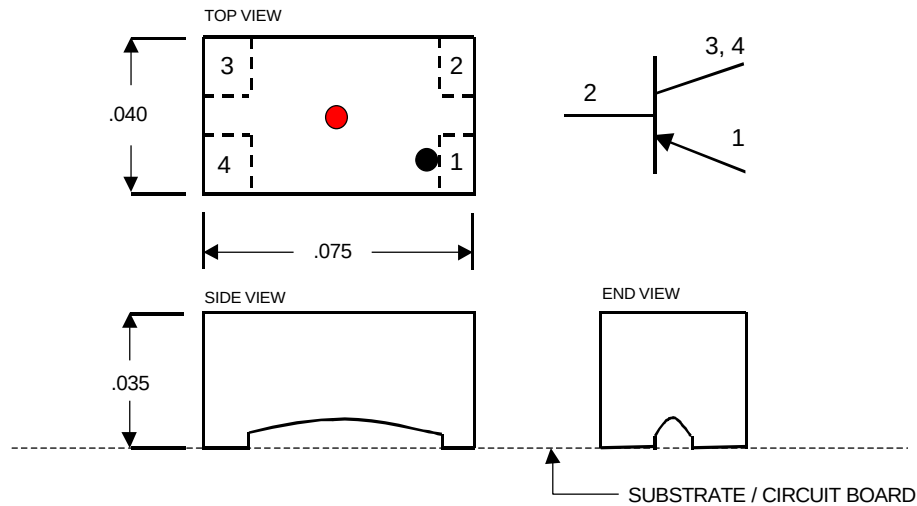
The LDT5087 (untinned) and LDT5087T (tinned) are PNP silicon transistors in very small, rugged, surface mount, 4-post ceramic packages (Micro International manufactured package p/n 4-075-1). The LDT5087 and LDT5087T meet the general specifications of the 2N5087 transistor. The 4-075-1 Micro-LID package is a 4-post, leadless ceramic carrier which can be provided with gold metallized or pre-tinned lands, and is approved for military, medical implant, sensor, and high reliability applications. The LDT5087 and LDT5087T can be provided with special feature options such as additional temperature cycling and screening.

Maximum Ratings:

Parameter	Symbol	Rating
Collector-Base Voltage	Vcbo	50 V
Collector-Emitter Voltage	Vceo	50 V
Emitter-Base Voltage	Vebo	5 V
Collector Current	Ic	100 mA
Total Dissipation	Pt	350 mW
Operating Junction Temperature	Tj	150°C
Storage Temperature	Tstg	-65°C to 150°C
Operating Temperature	Toper	-55°C to 125°C

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Outline / Schematic:



Dimensions / Marking:

Length	$.075'' \pm .003''$	Post 1 (Emitter)	$.015'' \times .010''$ typ
Width	$.040'' \pm .003''$	Post 2 (Base)	$.015'' \times .010''$ typ
Height	$.035'' \pm .003''$	Post 3,4 (Collector)	$.015'' \times .012''$ typ

Marking on back of package : Black Dot over Emitter and Red Dot in Center
(post down configuration)

Standard In-Process Screening Requirements:

- Semiconductor die and Micro-LID package visual inspection
- Wire pull test
- 24 hour stabilization bake at 150°C
- 10 temperature cycles from -55°C to 125°C
- 100% electrical test of dc characteristics at 25°C
- Final visual inspection

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Electrical Characteristics (25 °C Ambient)

Parameter	Symbol	Min	Typ	Max	Units
Collector-Base Breakdown $I_c = 100 \mu A, I_e = 0$	BVcbo	50	--	--	V
Collector-Emitter Breakdown* $I_b = 0, I_c = 1 \text{ mA}$	BVceo	50	--	--	V
Emitter-Base Breakdown $I_c = 0, I_e = 10 \mu A$	BVebo	5	--	--	V
Collector-Base Cutoff Current $V_{cb} = 35 \text{ V}$	Icbo	--	--	50	nA
DC Forward Current Gain* $I_c = 100 \mu A, V_{ce} = 5 \text{ V}$	Hfe	250	--	800	
Collector-Emitter Saturation $I_c = 10 \text{ mA}, I_b = 1 \text{ mA}$	Vce (sat)	--	--	.3	V
Base-Emitter Saturation $I_c = 10 \text{ mA}, I_b = 1 \text{ mA}$	Vbe (sat)	--	--	.85	V
Collector Capacitance $V_{cb} = 10 \text{ V}, I_e = 0$ $f = 1 \text{ MHz}$	Cobo	--	--	4	pF

* Pulse test, pulse width $\leq 300 \mu\text{sec}$, duty cycle $\leq 2\%$
